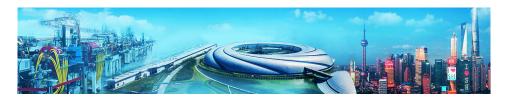
International Workshop on Breakdown Science and High Gradient Technology (HG2018)



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LLRF layout and design for X-band test setup at SINAP

Wednesday 6 June 2018 14:25 (25 minutes)

The High power test stand located in Jiading Campus at SINAP had finished conditioning two C band accelerate tube since 2018. We are also builindg our X band LLRF system, which will be put into use this year. In this presentation, the LLRF system in the test stand will be introduced, which had fufilled the functions like breakdown data monitoring and analyzation, modulator communication and trigger allocation.

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